

# Advanced and Customizable Camera Technology for Direct Detection of X-rays



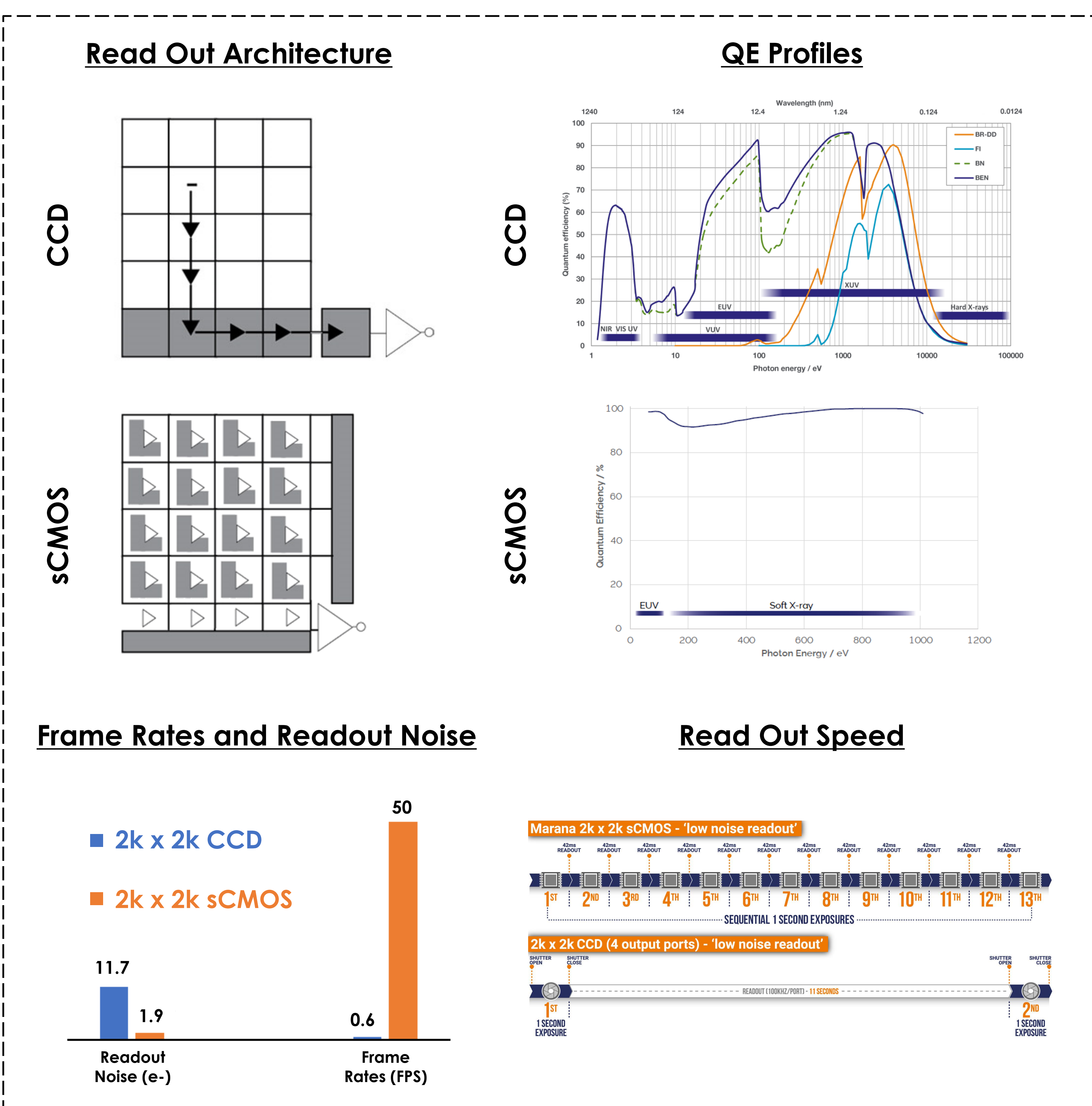
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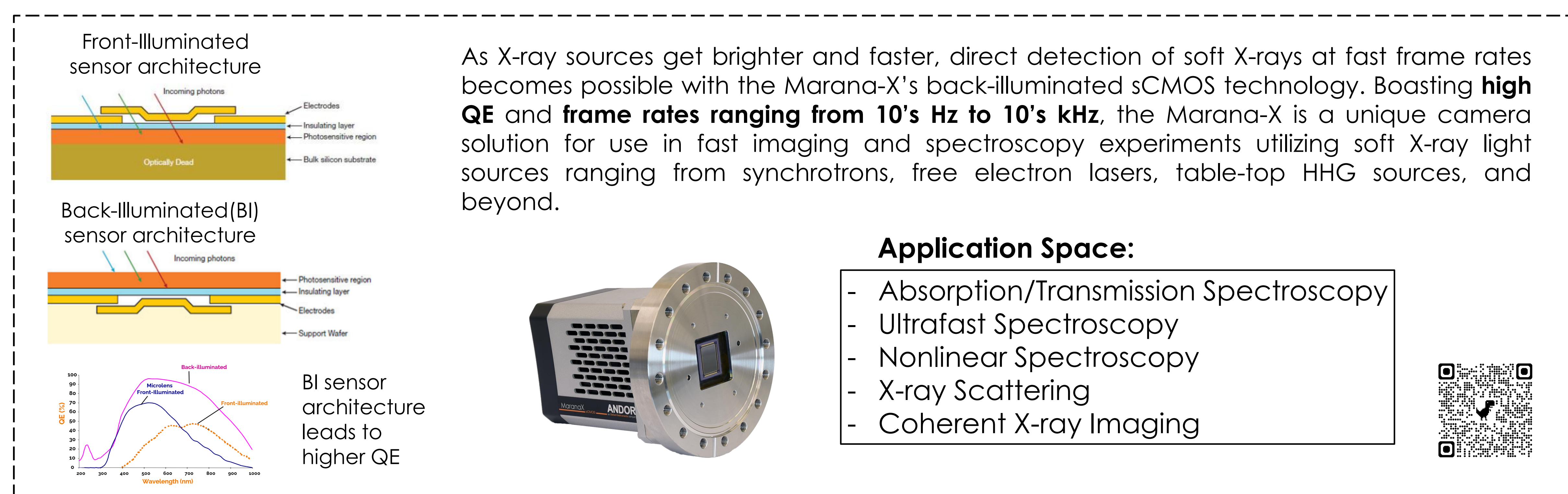
**Abstract.** Development of soft X-ray (20 eV to 10 keV) sources has led to an increasingly wide application of X-ray spectroscopy, microscopy, and tomography for studying material and biological systems. As experimental applications of these methods continue to grow, detection needs in the soft X-ray regime are becoming increasingly demanding and diverse. It is important that X-ray camera technology develops to accommodate these needs, whether they be complex experimental geometries, a desire for high-throughput capabilities, or large fields of view. Equally as important is that detector sensitivity and noise profiles are not compromised in this pursuit.

We present several detection solutions for complex and high-speed soft X-ray measurements. A back-illuminated X-ray sCMOS camera is shown, possessing full frame rates at least an order of magnitude faster than conventional CCD technology. Examples of custom CCD cameras will be shown to illustrate how X-ray detectors can be modified to accommodate unique experimental geometries. Further discussion will be framed around how camera technology can facilitate a continual evolution in soft X-ray methodologies housed in both small research group settings and larger beamline facilities.

## Technical differentiation of soft X-ray CCD and sCMOS cameras.



## Marana-X: Back-Illuminated sCMOS for fast and direct soft X-ray measurements.



## X-ray CCD cameras optimized for particular experimental configurations.

